

# FDD2612

# 200V N-Channel PowerTrench® MOSFET

## **General Description**

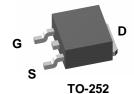
This N-Channel MOSFET has been designed specifically to improve the overall efficiency of DC/DC converters using either synchronous or conventional switching PWM controllers. It has been optimized for low gate charge, low  $R_{DS(ON)}$  and fast switching speed.

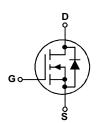
## **Applications**

DC/DC converter

### **Features**

- 4.9 A, 200 V.  $R_{DS(ON)} = 720 \text{ m}\Omega$  @  $V_{GS} = 10 \text{ V}$
- High performance trench technology for extremely low  $R_{\mbox{\scriptsize DS(ON)}}$
- High power and current handling capability
- Fast switching speed
- Low gate charge (8nC typical)





Absolute Maximum Ratings T<sub>A</sub>=25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
V <sub>DSS</sub>	Drain-Source Voltage		200	V
$V_{GSS}$	Gate-Source Voltage		± 20	V
I <sub>D</sub>	Drain Current - Continuous (N	Note 1a)	4.9	Α
	- Pulsed		10	
P <sub>D</sub>	Power Dissipation	(Note 1)	42	W
	1)	Note 1a)	3.8	
	1)	Note 1b)	1.6	
$T_J$ , $T_{STG}$	Operating and Storage Junction Temperature F	Range	-55 to +175	°C

## **Thermal Characteristics**

R <sub>eJC</sub>	Thermal Resistance, Junction-to-Case	(Note 1)	3.5	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	40	°C/W
R <sub>θJA</sub>	Thermal Resistance, Junction-to-Ambient	(Note 1b)	96	°C/W

**Package Marking and Ordering Information** 

Device Marking	Device	Reel Size	Tape width	Quantity
FDD2612	FDD2612	13"	16mm	2500 units

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Drain-Sc	ource Avalanche Ratings (Not	re 2)		ı	I	I
W <sub>DSS</sub>	Drain-Source Avalanche Energy	Single Pulse, $V_{DD} = 100 \text{ V}$ , $I_D = 1.5 \text{ A}$			90	mJ
I <sub>AR</sub>	Drain-Source Avalanche Current				1.5	Α
Off Char	acteristics					
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, \qquad I_{D} = 250 \mu\text{A}$	200			V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 250 μA, Referenced to 25°C		246		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	$V_{DS} = 160 \text{ V}, \qquad V_{GS} = 0 \text{ V}$			1	μΑ
I <sub>GSSF</sub>	Gate-Body Leakage, Forward	$V_{GS} = 20 \text{ V}, \qquad V_{DS} = 0 \text{ V}$			100	nA
I <sub>GSSR</sub>	Gate-Body Leakage, Reverse	$V_{GS} = -20 \text{ V}$ , $V_{DS} = 0 \text{ V}$			-100	nA
On Char	acteristics (Note 2)					
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}$ , $I_D = 250 \mu A$	2	4	4.5	V
$\Delta V_{GS(th)} \over \Delta T_J$	Gate Threshold Voltage Temperature Coefficient	$I_D$ = 250 $\mu$ A, Referenced to 25°C		- 8.6		mV/°C
R <sub>DS(on)</sub>	Static Drain–Source On Resistance	$V_{GS} = 10 \text{ V}, \qquad I_D = 1.5 \text{ A}$ $V_{GS} = 10 \text{ V},  I_D = 1.5 \text{ A}, T_J = 125^{\circ}\text{C}$		600 1125	720 1422	mΩ
$I_{D(on)}$	On-State Drain Current	$V_{GS} = 10 \text{ V}, \qquad V_{DS} = 10 \text{ V}$	5			Α
<b>g</b> FS	Forward Transconductance	$V_{DS} = 10 \text{ V}, \qquad I_{D} = 1.5 \text{ A}$		4.4		S
Dynamic	Characteristics					
C <sub>iss</sub>	Input Capacitance	$V_{DS} = 100 \text{ V},  V_{GS} = 0 \text{ V},$		234		pF
Coss	Output Capacitance	f = 1.0 MHz		18		pF
$C_{\text{rss}}$	Reverse Transfer Capacitance			8		pF
Switchin	g Characteristics (Note 2)					
$t_{\text{d(on)}}$	Turn-On Delay Time	$V_{DD} = 100 \text{ V}, \qquad I_D = 1 \text{ A},$		6	12	ns
$t_r$	Turn-On Rise Time	$V_{GS} = 10 \text{ V}, \qquad R_{GEN} = 6 \Omega$		6	12	ns
$t_{\text{d(off)}}$	Turn-Off Delay Time			17	30	ns
t <sub>f</sub>	Turn-Off Fall Time			8	16	ns
$Q_g$	Total Gate Charge	$V_{DS} = 100 \text{ V},  I_{D} = 1.5 \text{ A},$		8	11	nC
$Q_{gs}$	Gate-Source Charge	V <sub>GS</sub> = 10 V		1.6		nC
$Q_{\text{gd}}$	Gate-Drain Charge			2.2		nC
Drain-S	ource Diode Characteristics	and Maximum Ratings				
Is	Maximum Continuous Drain-Sourc				3.2	Α
V <sub>SD</sub>	Drain–Source Diode Forward Voltage	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 3.2 A (Note 2)		0.8	1.2	V

#### Notes

1. R<sub>8JA</sub> is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R<sub>8JC</sub> is guaranteed by design while R<sub>8CA</sub> is determined by the user's board design.



a)  $R_{\theta JA} = 40^{\circ} C/W$  when mounted on a  $1 in^2$  pad of 2 oz copper



b)  $R_{\theta JA} = 96^{\circ}CW$  when mounted on a minimum pad.

Scale 1:1 on letter size paper

2. Pulse Test: Pulse Width < 300 $\mu$ s, Duty Cycle < 2.0%

3. Maximum current is calculated as:  $\sqrt{\frac{P_D}{R_{DS(G)}}}$ 

 $where \ P_D \ is \ maximum \ power \ dissipation \ at \ T_C = 25^{\circ}C \ and \ R_{DS(on)} \ is \ at \ T_{J(max)} \ and \ V_{GS} = 10V. \quad Package \ current \ limitation \ is \ 21A \ and \ V_{GS} = 10V. \ Package \ current \ limitation \ is \ 21A \ and \ V_{GS} = 10V. \ Package \ current \ limitation \ is \ 21A \ and \ V_{GS} = 10V. \ Package \ current \ limitation \ is \ 21A \ and \ V_{GS} = 10V. \ Package \ current \ limitation \ is \ 21A \ and \ V_{GS} = 10V. \ Package \ current \ limitation \ limitation$ 

# **Typical Characteristics**

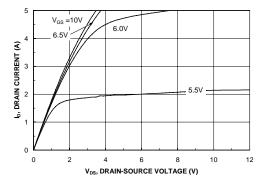


Figure 1. On-Region Characteristics.

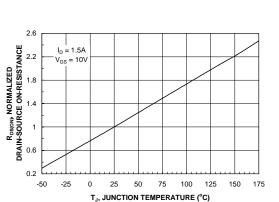


Figure 3. On-Resistance Variation with Temperature.

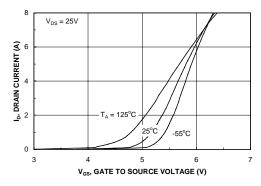


Figure 5. Transfer Characteristics.

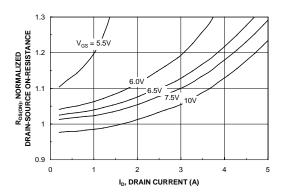


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

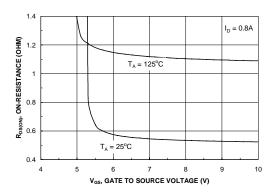


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

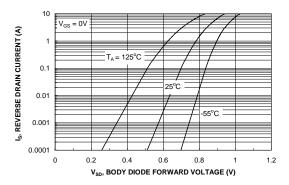
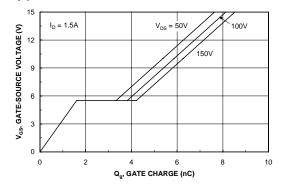


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

# **Typical Characteristics**



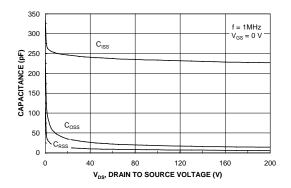
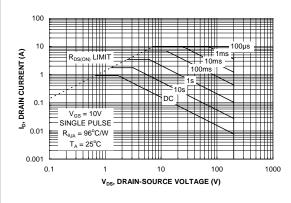


Figure 7. Gate Charge Characteristics.





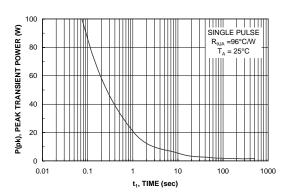


Figure 9. Maximum Safe Operating Area.

Figure 10. Single Pulse Maximum Power Dissipation.

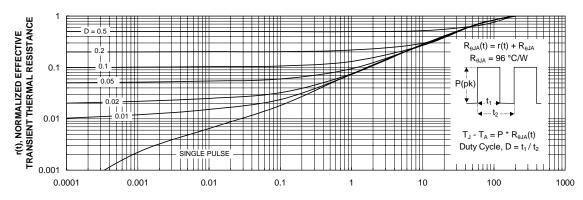


Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1b. Transient thermal response will change depending on the circuit board design.

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